

# International I<sup>OR</sup> Rectifier

## Typical Applications

- Anti-lock Braking Systems (ABS)
- Electronic Fuel Injection
- Air bag

## Benefits

- Advanced Process Technology
- Dual N-Channel MOSFET
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Repetitive Avalanche Allowed up to Tjmax
- Automotive [Q101] Qualified
- Lead-Free

## Description

Specifically designed for Automotive applications, these HEXFET® Power MOSFET's in a Dual SO-8 package utilize the lastest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these Automotive qualified HEXFET Power MOSFET's are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

The 175°C rating for the SO-8 package provides improved thermal performance with increased safe operating area and dual MOSFET die capability make it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.

## Absolute Maximum Ratings

	Parameter	Max.	Units
V <sub>DS</sub>	Drain-Source Voltage	55	V
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	5.1	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	4.2	A
I <sub>DM</sub>	Pulsed Drain Current①	42	
P <sub>D</sub> @ T <sub>A</sub> = 25°C	Maximum Power Dissipation③	2.4	W
P <sub>D</sub> @ T <sub>A</sub> = 70°C	Maximum Power Dissipation③	1.7	W
	Linear Derating Factor	16	mW/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy②	140	mJ
I <sub>AR</sub>	Avalanche Current①	5.1	A
E <sub>AR</sub>	Repetitive Avalanche Energy	See Fig. 14, 15, 16	mJ
T <sub>J</sub> , T <sub>STG</sub>	Junction and Storage Temperature Range	-55 to + 175	°C

## Thermal Resistance

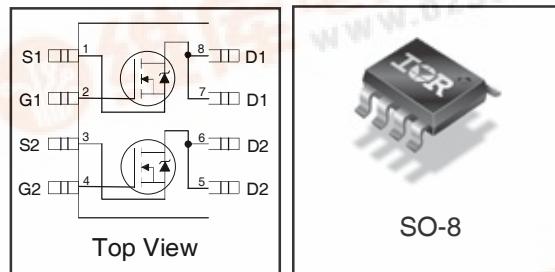
	Parameter	Max.	Units
R <sub>θJA</sub>	Maximum Junction-to-Ambient ③	62.5	°C/W

PD - 96108

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HEXFET® Power MOSFET

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
55V	0.050@V <sub>GS</sub> = 10V	5.1A
	0.065@V <sub>GS</sub> = 4.5V	4.42A



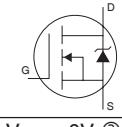
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## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.052	—	$\text{V}^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.043	0.050	$\Omega$	$V_{\text{GS}} = 10\text{V}$ , $I_D = 5.1\text{A}$ ②
		—	0.056	0.065		$V_{\text{GS}} = 4.5\text{V}$ , $I_D = 4.42\text{A}$ ②
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	1.0	—	—	V	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$
$g_{\text{fs}}$	Forward Transconductance	10.4	—	—	S	$V_{\text{DS}} = 10\text{V}$ , $I_D = 5.2\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	2.0	$\mu\text{A}$	$V_{\text{DS}} = 44\text{V}$ , $V_{\text{GS}} = 0\text{V}$
		—	—	25		$V_{\text{DS}} = 44\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $T_J = 150^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
$Q_g$	Total Gate Charge	—	29	44	nC	$I_D = 5.2\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	2.9	4.4		$V_{\text{DS}} = 44\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	7.3	11		$V_{\text{GS}} = 10\text{V}$
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	9.2	—	ns	$V_{\text{DD}} = 28\text{V}$
$t_r$	Rise Time	—	7.7	—		$I_D = 1.0\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	31	—		$R_G = 6.0\Omega$
$t_f$	Fall Time	—	12.5	—		$V_{\text{GS}} = 10\text{V}$ ②
$C_{\text{iss}}$	Input Capacitance	—	780	—	pF	$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	190	—		$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	66	—		$f = 1.0\text{MHz}$

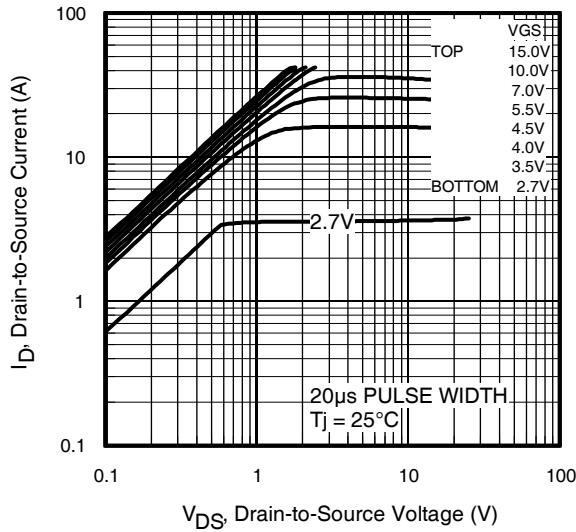
## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	2.4	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	42		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.2	V	$T_J = 25^\circ\text{C}$ , $I_S = 2.6\text{A}$ , $V_{\text{GS}} = 0\text{V}$ ②
$t_{\text{rr}}$	Reverse Recovery Time	—	51	77	ns	$T_J = 25^\circ\text{C}$ , $I_F = 2.6\text{A}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	76	114	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ②

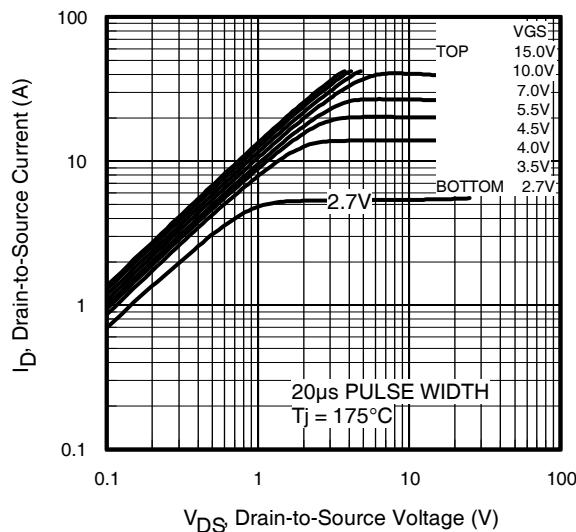
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.  
 ② Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .

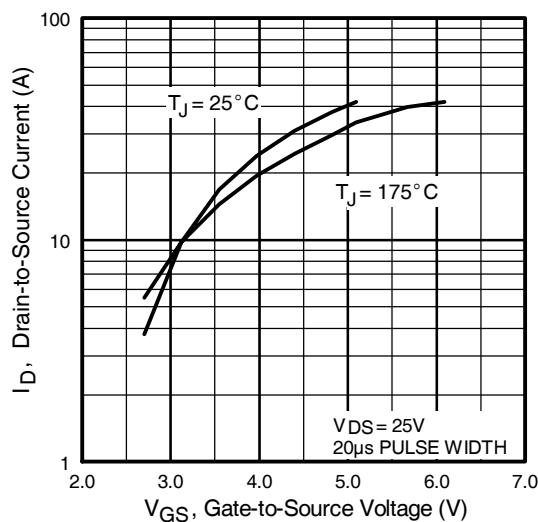
③ Surface mounted on FR-4 board,  $t \leq 10\text{sec}$ .



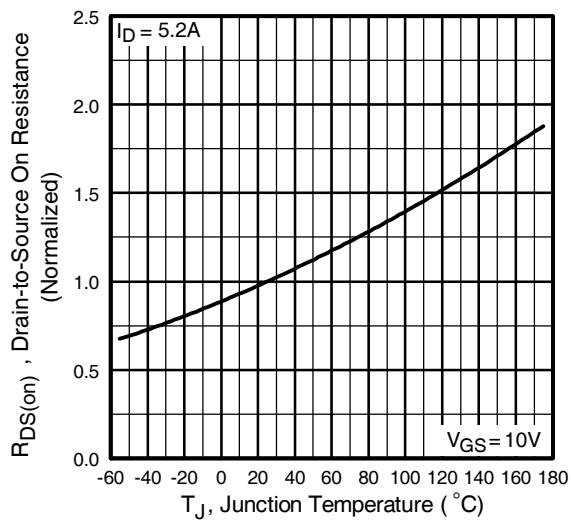
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



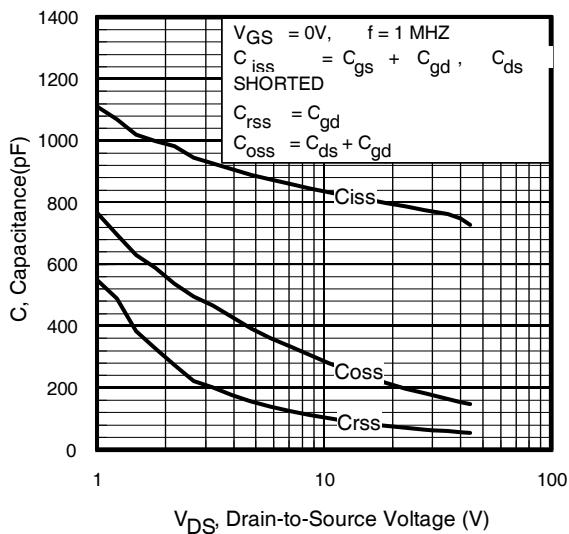
**Fig 3.** Typical Transfer Characteristics



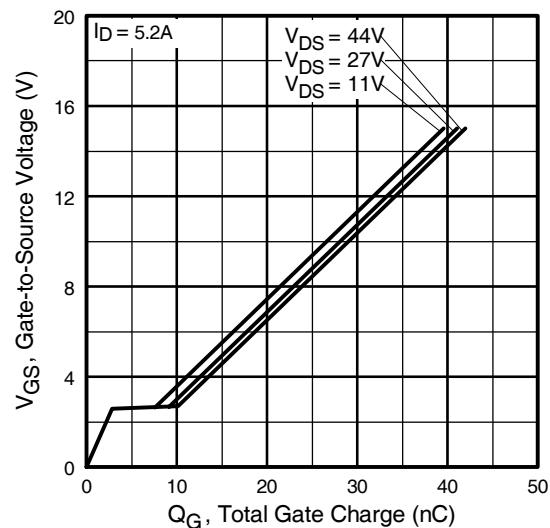
**Fig 4.** Normalized On-Resistance  
Vs. Temperature

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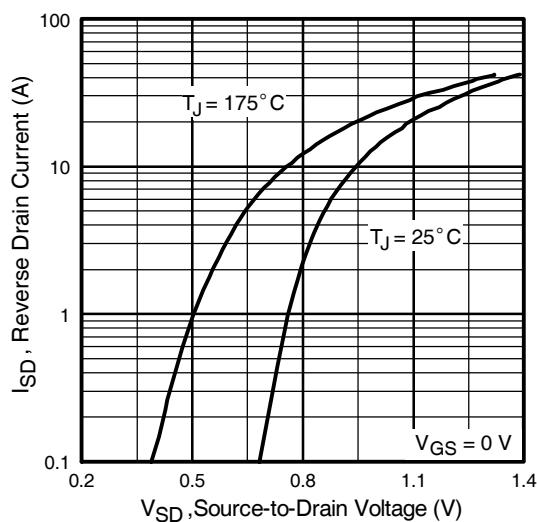
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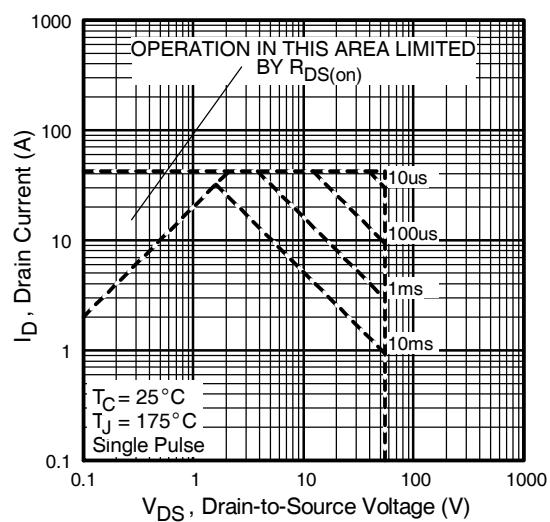
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



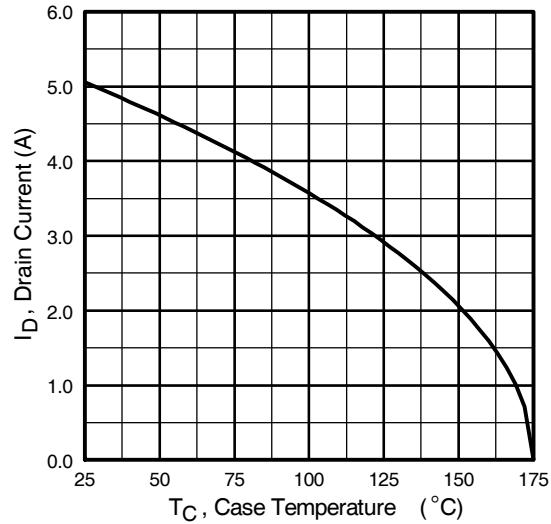
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



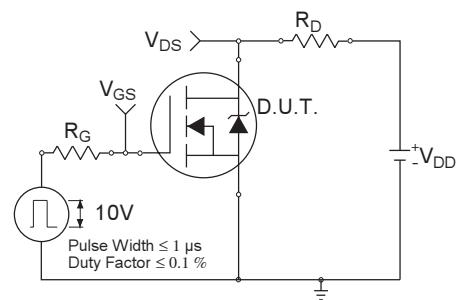
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



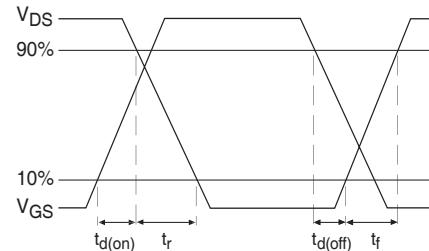
**Fig 8.** Maximum Safe Operating Area



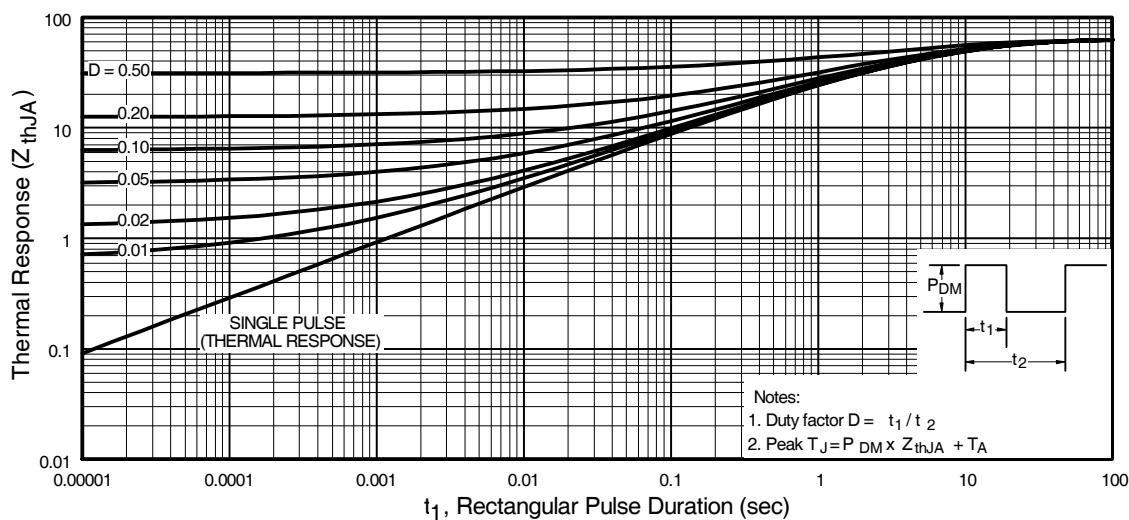
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



**Fig 10a.** Switching Time Test Circuit



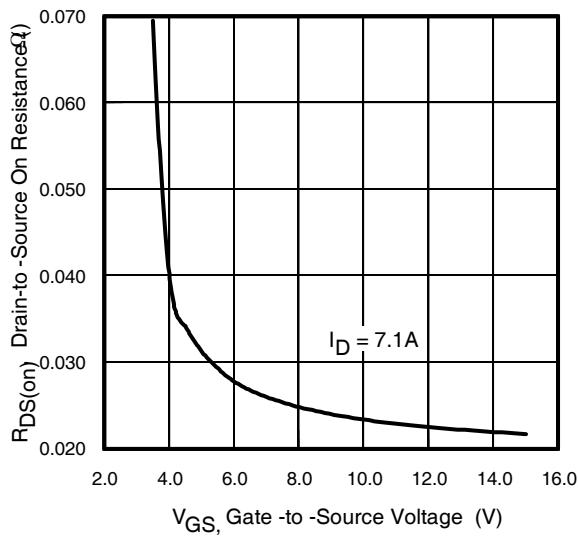
**Fig 10b.** Switching Time Waveforms



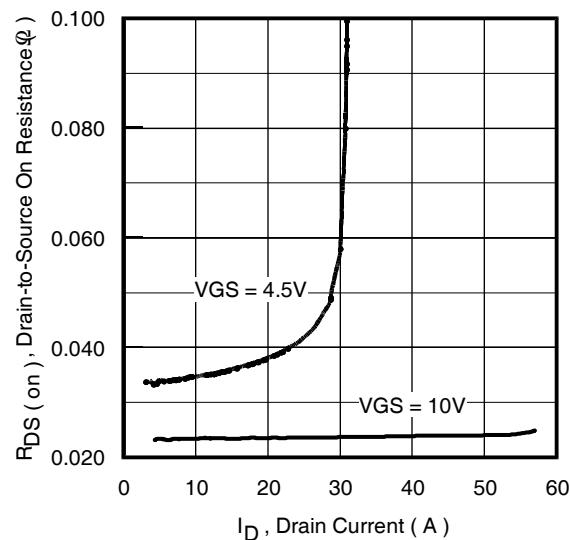
**Fig 10.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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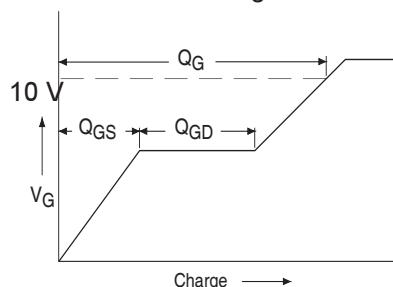
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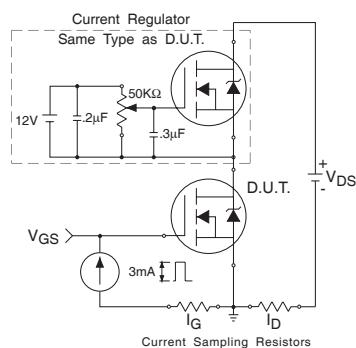
**Fig 11.** Typical On-Resistance Vs.  
Gate Voltage



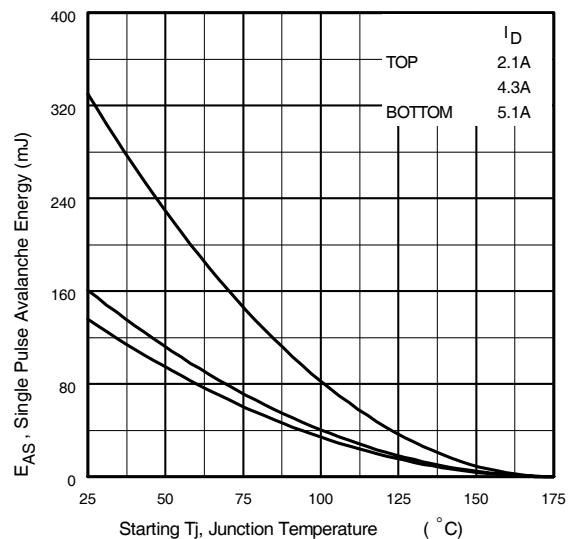
**Fig 12.** Typical On-Resistance Vs.  
Drain Current



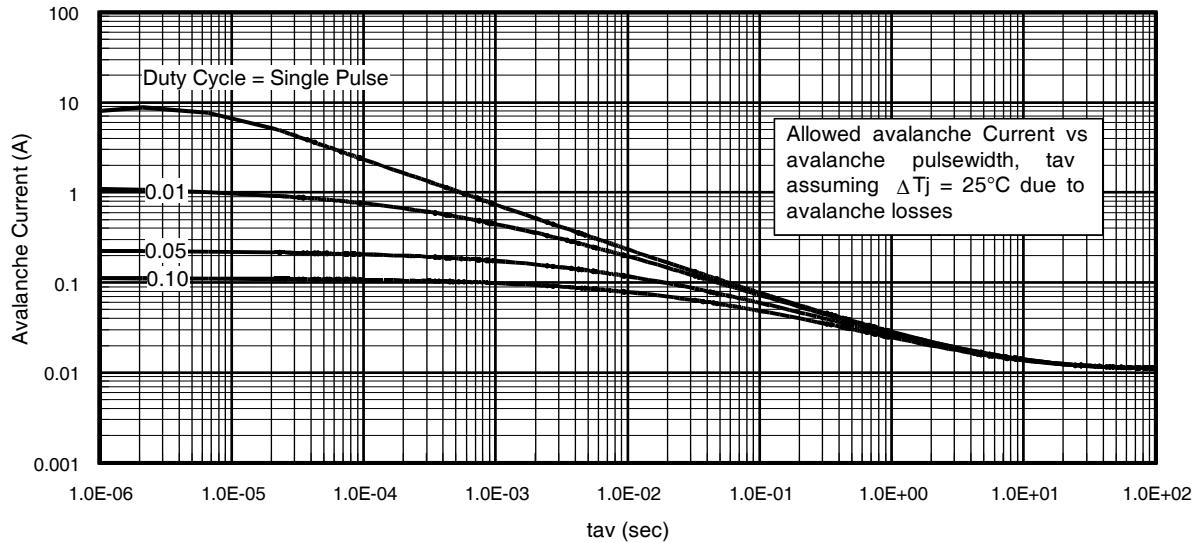
**Fig 13a.** Basic Gate Charge Waveform



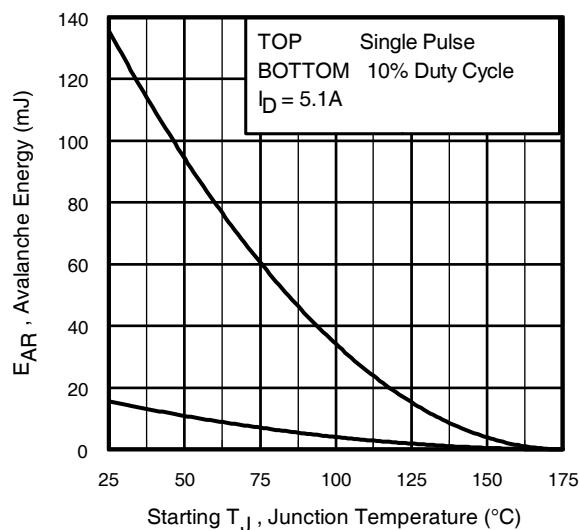
**Fig 13b.** Gate Charge Test Circuit



**Fig 14.** Maximum Avalanche Energy  
Vs. Drain Current



**Fig 15.** Typical Avalanche Current Vs.Pulsewidth



**Fig 16.** Maximum Avalanche Energy Vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 15, 16:**  
**(For further info, see AN-1005 at [www.irf.com](http://www.irf.com))**

1. Avalanche failures assumption:  
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4.  $P_D(\text{ave})$  = Average power dissipation per single avalanche pulse.
5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^\circ\text{C}$  in Figure 15, 16).
- $t_{av}$  = Average time in avalanche.
- $D$  = Duty cycle in avalanche =  $t_{av}/f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$P_D(\text{ave}) = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

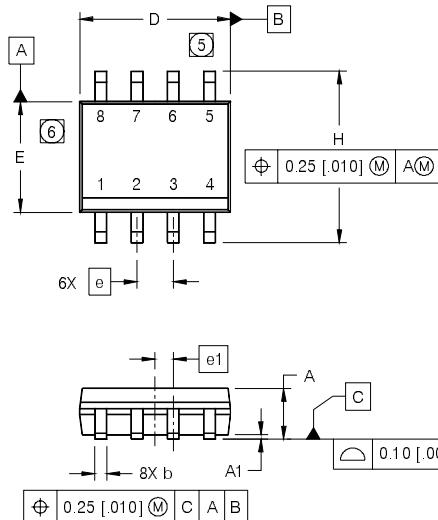
$$I_{av} = 2 \Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_D(\text{ave}) \cdot t_{av}$$

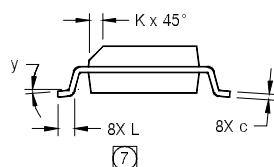
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## SO-8 Package Outline

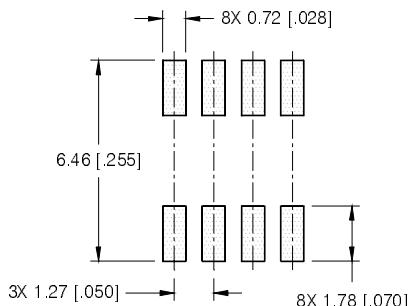
Dimensions are shown in millimeters (inches)



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°

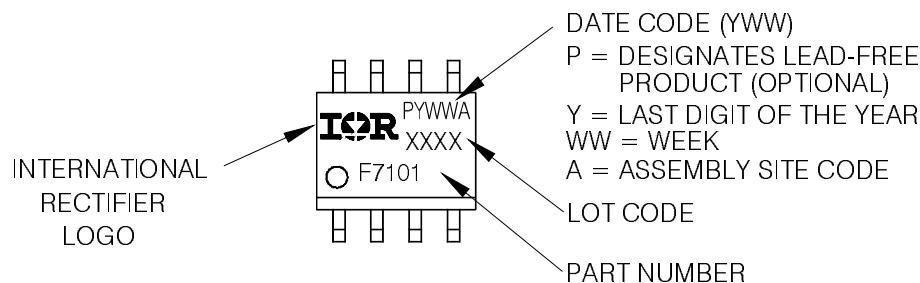


### FOOTPRINT



## SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)



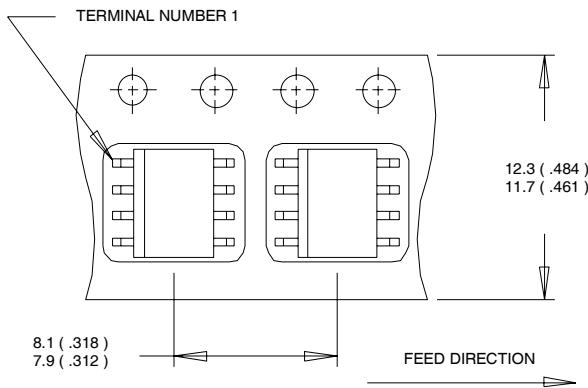
Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

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## SO-8 Tape and Reel

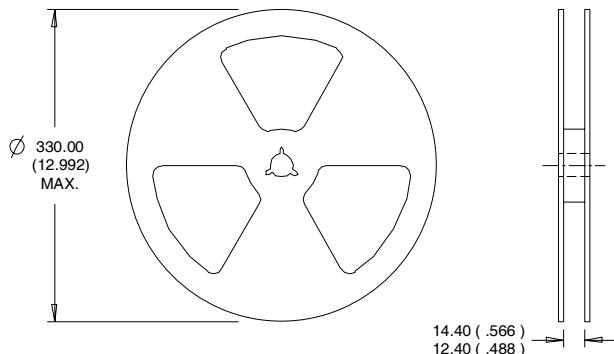
Dimensions are shown in millimeters (inches)

**IRF7341QPbF**



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Autyomotive [Q101] market.  
Qualification Standards can be found on IR's Web site.

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